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<b>**CONTINUING DATA VERIFIED:</b> <i>None</i>					
<b>** FOREIGN APPLICATIONS VERIFIED:</b> JAPAN 2001-78362 03/19/2001 JAPAN 2001-78363 03/19/2001					
PG-PUB		DO NOT PUBLISH <input checked="" type="checkbox"/>		RESCIND <input type="checkbox"/>	
Foreign priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials				ATTORNEY DOCKET NO 12844.3US01	
TITLE : Method and apparatus for automatically testing semiconductor device					

Amount Due Date Paid		Assistant Examiner
<input type="checkbox"/> <b>TERMINAL</b> <b>DISCLAIMER</b>		Primary Examiner
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